





Al based smart solar arc-fault circuit interrupter solution

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Center

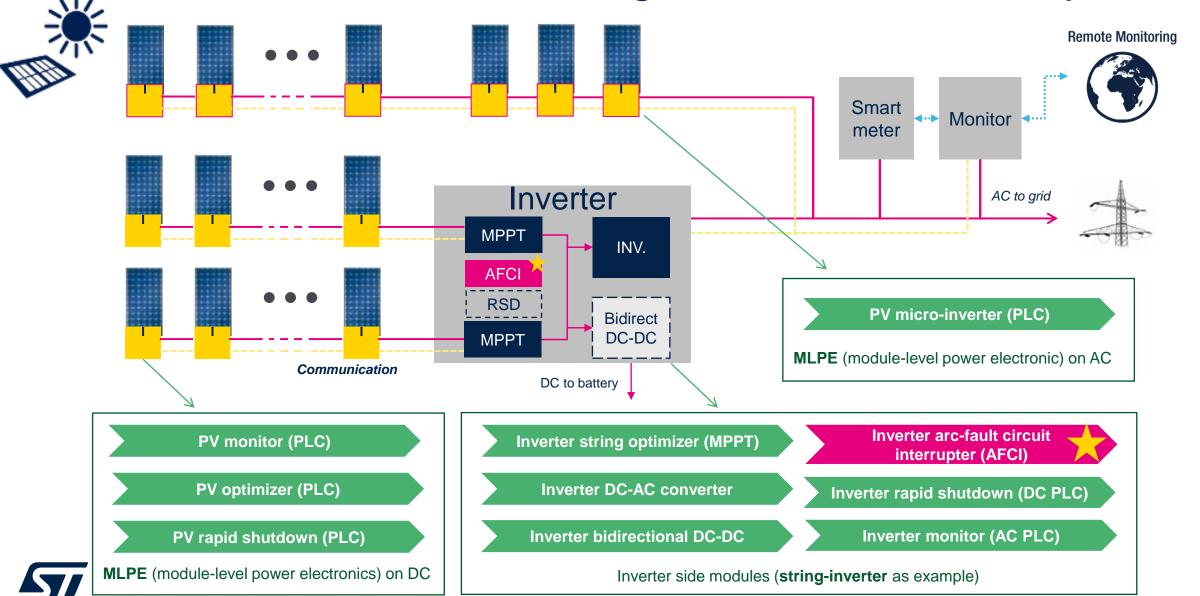
Power & Energy Competence



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ST reference designs for smart solar systems

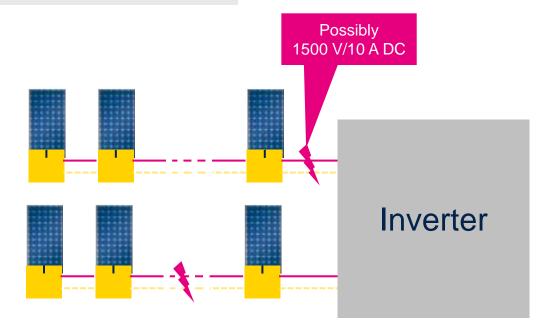


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The risks of arc-fault

Factors that may cause arcs

- Aging
- Weather variation
- Harsh environment
- Human factors















Arc-fault detection standard—UL1699B



Standard for safety

• Photovoltaic (PV) DC arc-fault circuit protection

Stationary Electrode

Moving Electrode

Lateral Adjustment

Sliding Block

Arcing test conditions

Test no.	Minimum I _{arc} (A) ^a	Impp (A)	Sep. rate (mm/s)	Vmpp (V) ^b	Voc (V) ^b	R _{tot} (ohms) ^b	Gap (mm)	
1	2.5	3.0	2.5	312.0	480.0	56.0	0.8	
2	7.0	8.0	5.0	318.0	490.0	21.0	8.0	
3c	14.0	16.0	5.0	318.0	490.0	11.0	1.1	
4	7.0	8.5	5.0	607.0	810.0	24.0	2.5	
Single module								
5	2.5	3.0	2.5	31.2	48.0	5.6	0.8	
6	7.0	8.0	5.0	31.8	49.0	2.1	0.8	

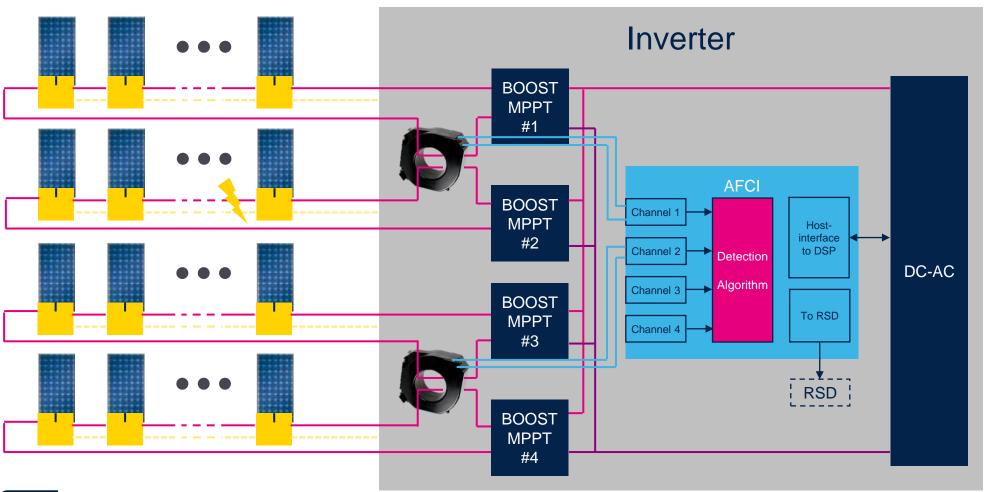
^a l_{arc} values in <u>Table 29.2</u> are representative of realistic arc events with one or two strings at full and low irradiance. It is expected that the AFCI shall meet compliance criteria below at intermediate current levels also.



^b These values are approximate.

^c Required for arcs in series with two parallel strings

STM32 + AI detector Field proven and future oriented system for AFCI

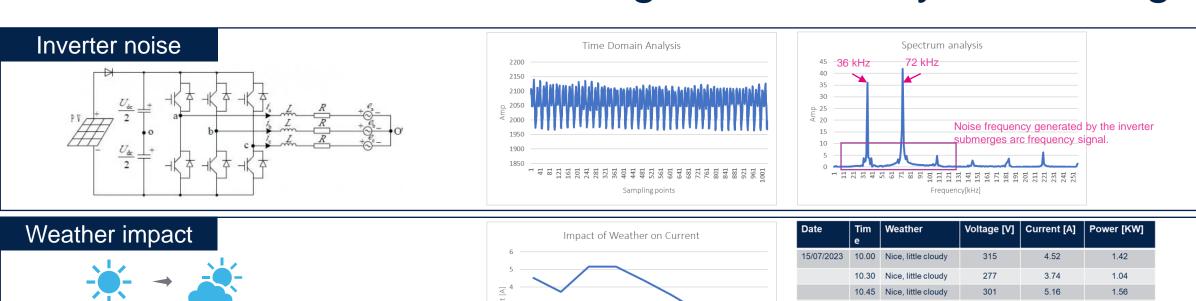






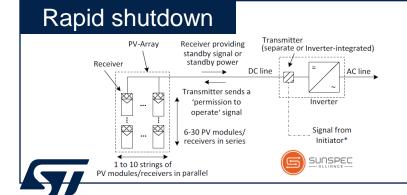


Challenges in AFCI system design



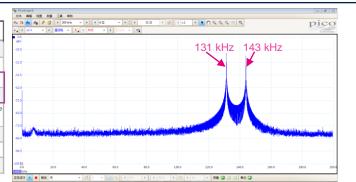


Date	Tim e	Weather	Voltage [V]	Current [A]	Power [KW]
15/07/2023	10.00	Nice, little cloudy	315	4.52	1.42
	10.30	Nice, little cloudy	277	3.74	1.04
	10.45	Nice, little cloudy	301	5.16	1.56
	11.00	Nice, little cloudy	300	5.16	1.55
	11.30	Nice, little cloudy	300	4.39	1.26
	11.45	Nice, little cloudy	320	3.55	1.10
	12.00	Cloudy	317	2.62	0.83
	12.15	Cloudy	334	2.36	0.79
	12.30	Cloudy	331	2.67	0.87

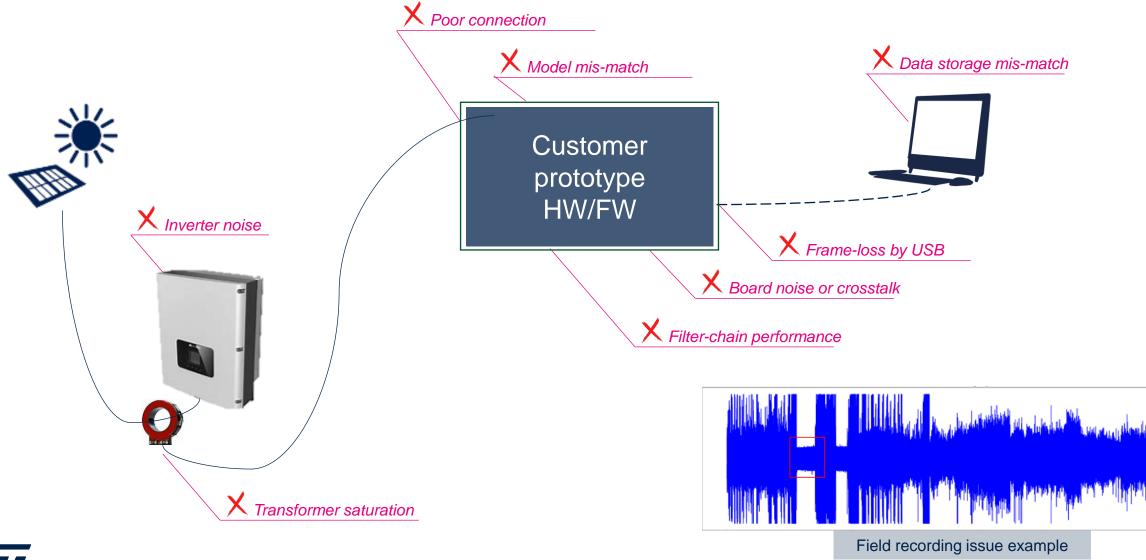


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Requirements of the Power Line Communication						
Symbol	Transmitter Specification	Min.	Nom.	Max.	Unit	Remark
$\mathbf{W_1}$	Logic 1 Code Word	{{-1, -1, -1, +1, +1, +1, -1, +1, +1, -1, +1}				+1 = mark, -1=space
W ₀	Logic 0 Code Word	{+1, +1, +1, -1, -1, -1, +1, -1, -1, +1, -1}				+1 = mark, -1=space
F _M	Mark Frequency	131.236875	131.25	131.263125	kHz	6.25kHz × 21
Fs	Space Frequency	143.735625	143.75	143.764375	kHz	6.25kHz × 23
Ts	Average Bit Period	5.119488	5.12	5.120512	ms	(Time to complete one full duty cycle)/219
T _T	Transmission Period	168.943104	168.96	168.976896	ms	3 Words
TQ	Quiet Period	901.029888	901.12	901.210112	ms	16 Words
Tc	Cycle Period	1069.972992	1070.08	1070.187008	ms	19 Words



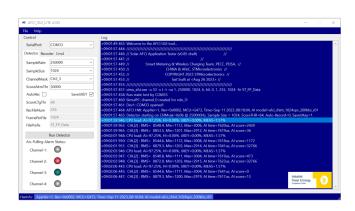
Possible issues in AFCI data processing

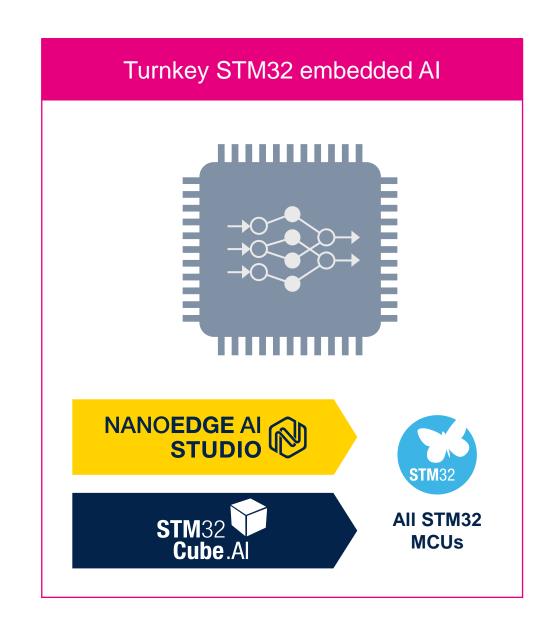


ST reference design for AFCI

Turnkey HW/SW reference design





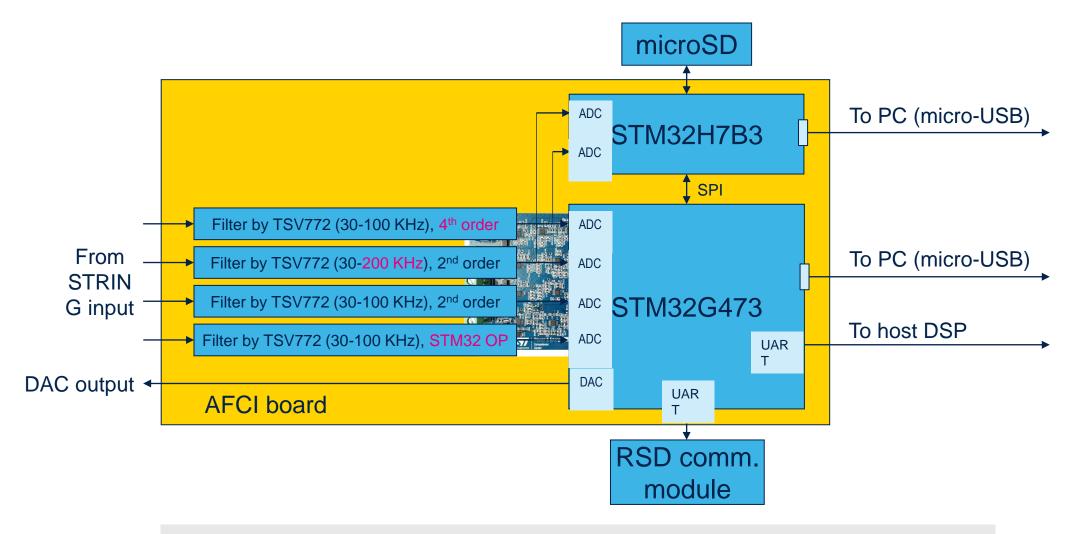




AFCI HW/FW reference design



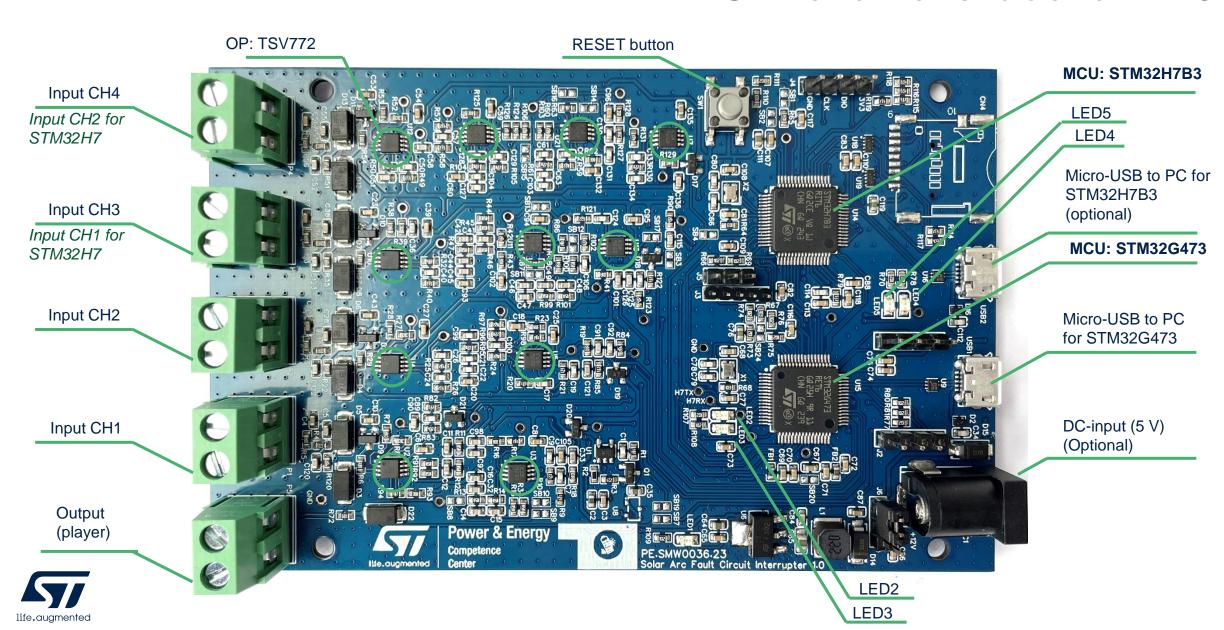
AFCI board hardware block diagram





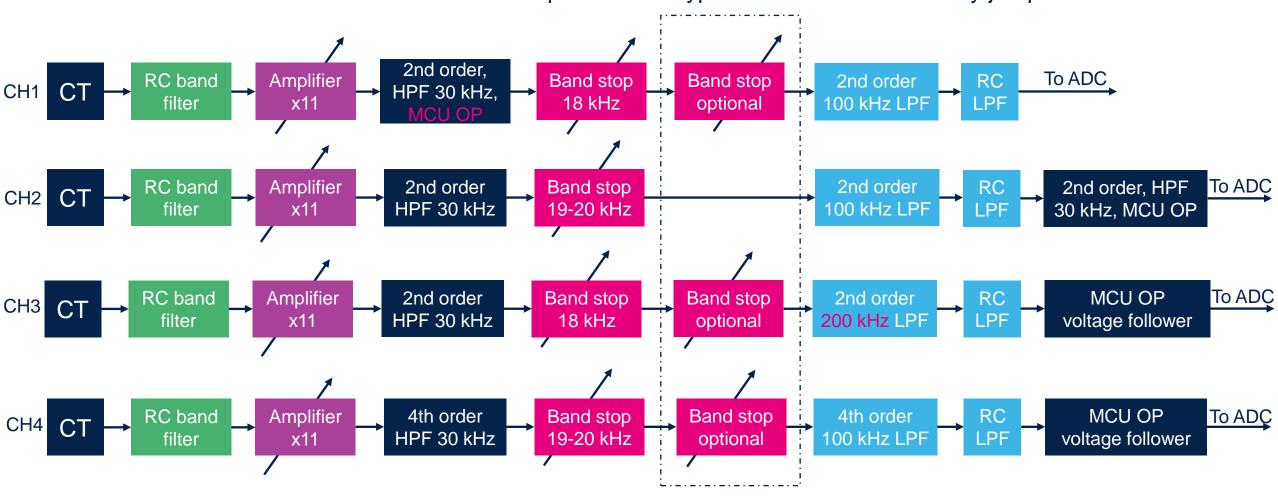
- The primary target of STM32H7B3 is to drive microSD card.
- STM32G473 or STM32H7B3 should be sufficient for customer AFCI product.

AFCI hardware board v1.0



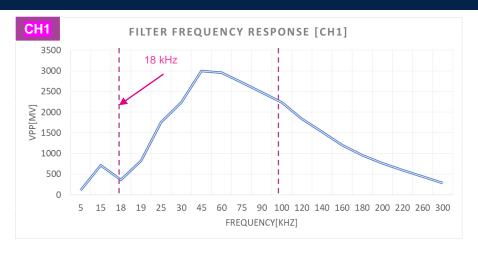
AFCI filter design

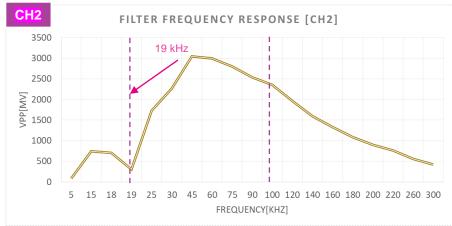
The 2nd band stop filters are bypassed in current board by jumpers

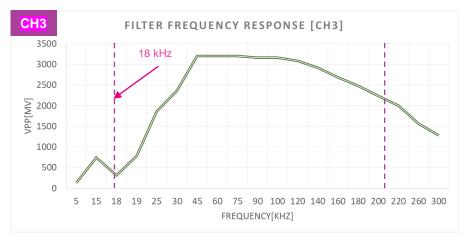


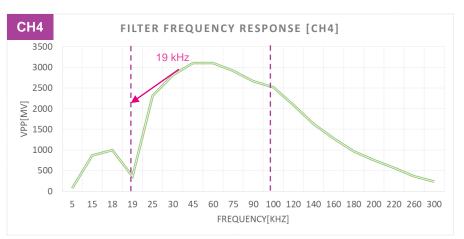
AFCI filter design

Frequency response of hardware filters



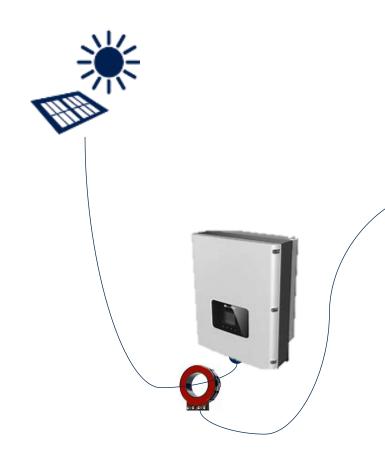








Connection in system





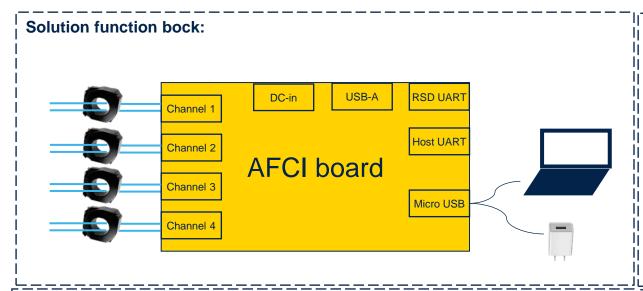


- Recorder mode: mainly used for data collection for model training.
- Detector mode: mainly used for NN model accuracy verification or ARC detection.
- Control mode: mainly used for firmware update, reset device, stop current mode etc.
- Others ...

AFCI GUI tool

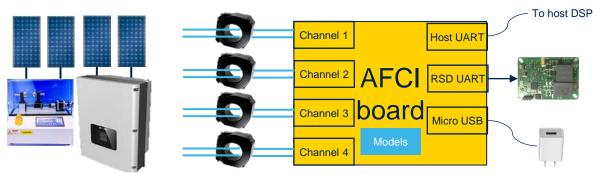


AFCI solution use-cases



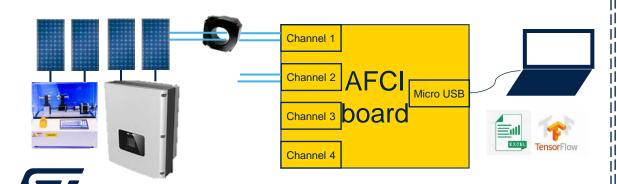
In-lab evaluation mode:

- Install in customer system for evaluation and competitor comparison.
- Enable parallel mode (4 channels), enable rapid shutdown (RSD) on arc-fault detected.



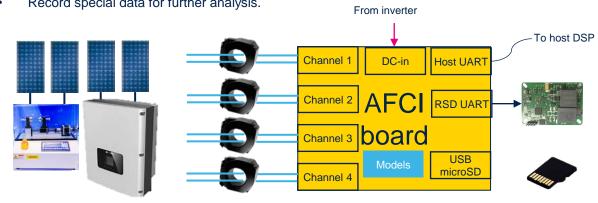
Data gathering mode:

- Read current, and possible voltage, and send to PC through USB.
- AFCI board powered by PC USB.



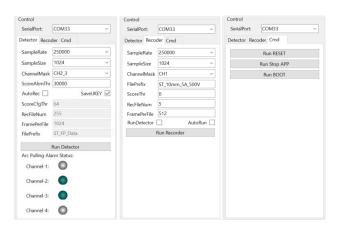
In-field evaluation mode:

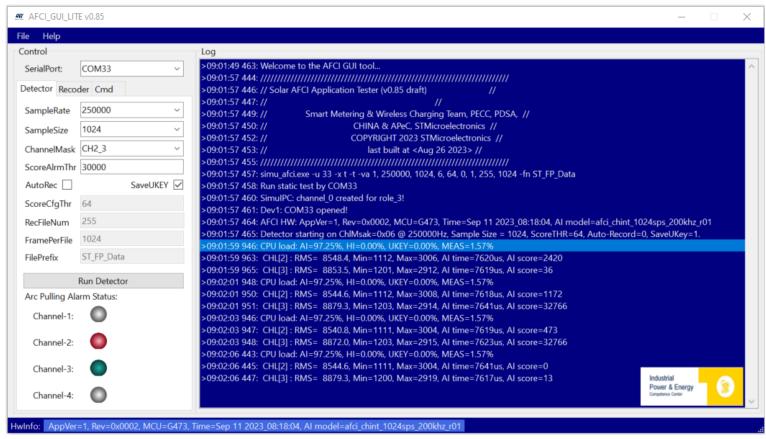
- Support customer field-trial.
- Record special data for further analysis.



AFCI GUI tool makes development easier

- Support detector mode
- Support recorder mode
- Support control command
- Support NVM configuration
- Support logging



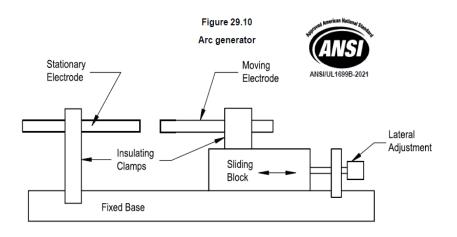


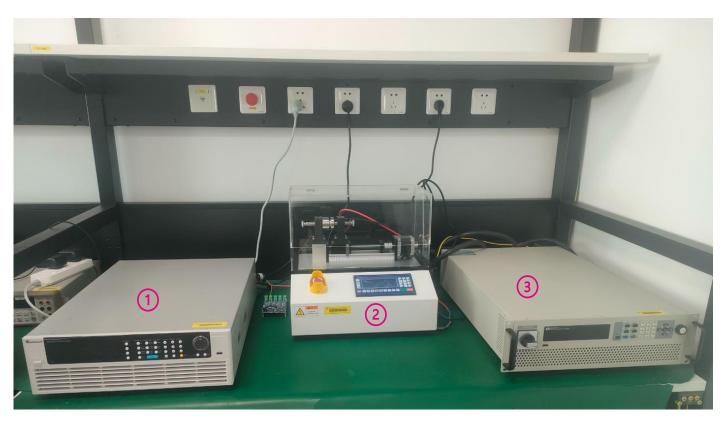


ST arc fault detection lab

Main instruments in AFCI lab

- 1. DC electronic load.
- 2. Arc generator
- 3. DC power supply



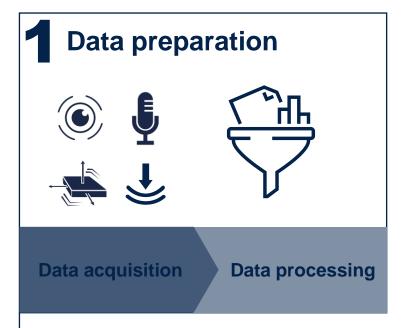


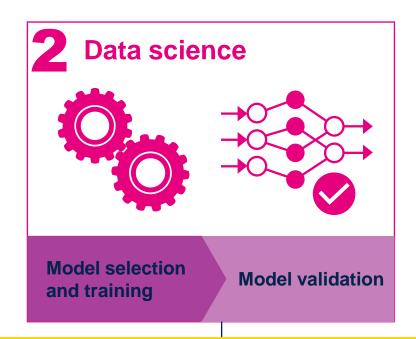


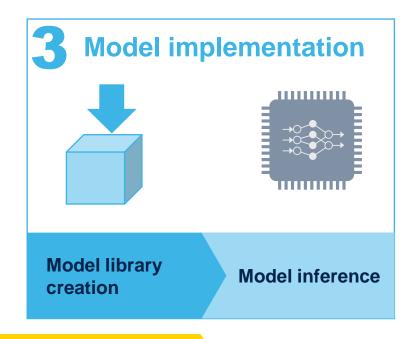
Al reference design



Overall AI development workflow









Automated edge AI software



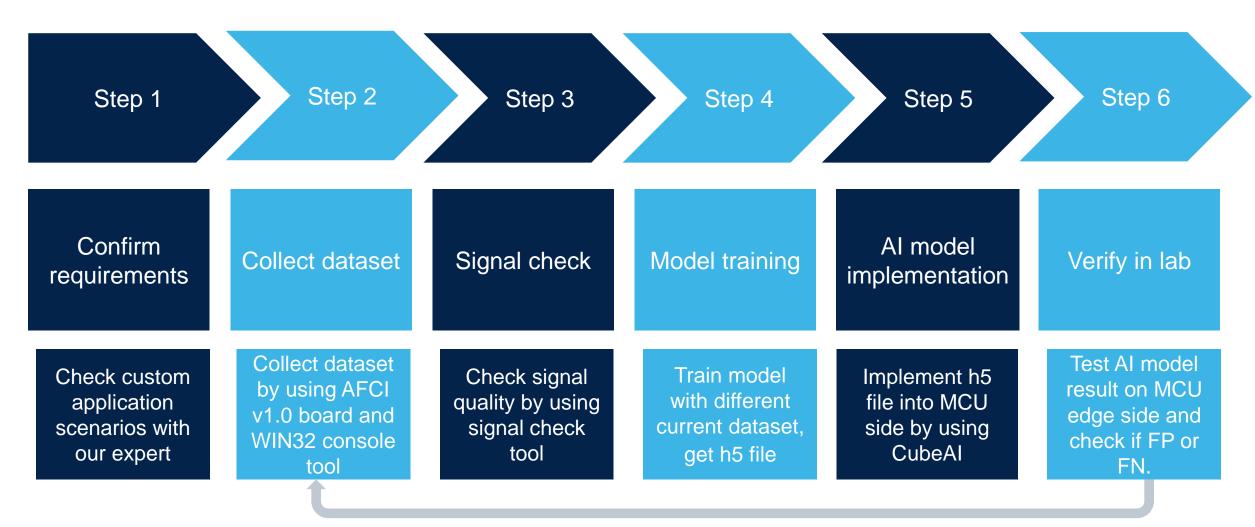


Edge Al toolkit





Step by step for AFCI project





Several rounds data collection to reach good performance

ST packages for AFCI

AFCI HW v1.0 board

Board including STM32G4 and STM32H7 for data collection and testing.



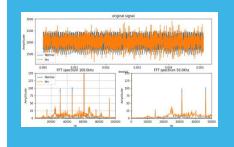
WIN32 console application

- Recorder
- Detector
- FW update

□ run_send_cmd.bat□ run_test_detector.bat□ run_test_record.bat□ simu_afci.exe

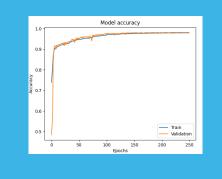
Signal check tool (exe file)

For analyzing signal quality.



AFCI AI model training (exe file)

For training the dataset for Al model.



AFCI FW project for STM32

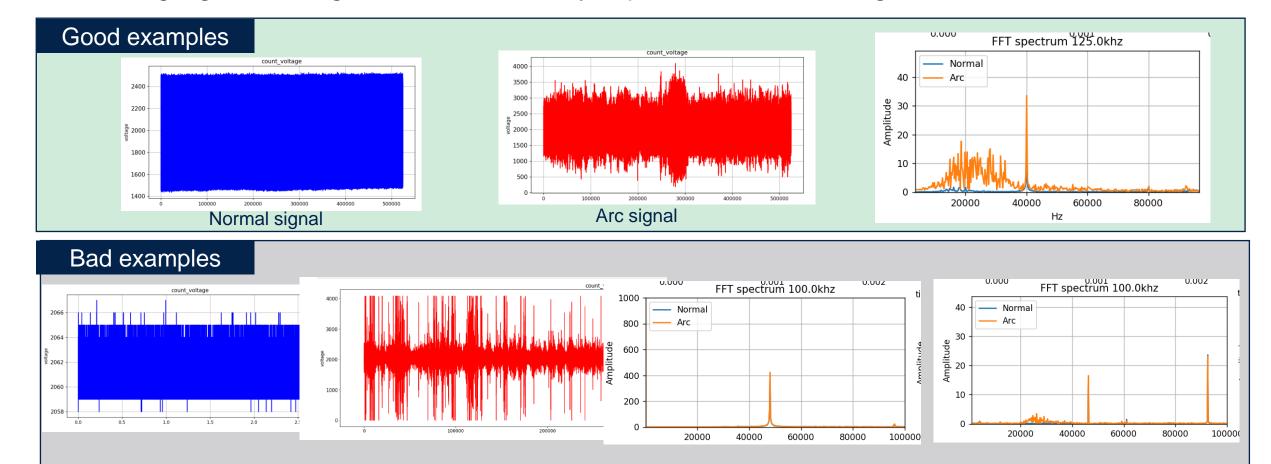
- Datalogging
- Al model real time processing
- Post-processing

User manual and guidelines



Signal checking

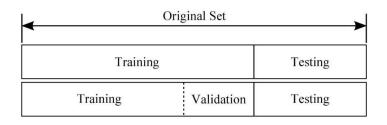
Checking signal with signal check tool is very important before training neural network.

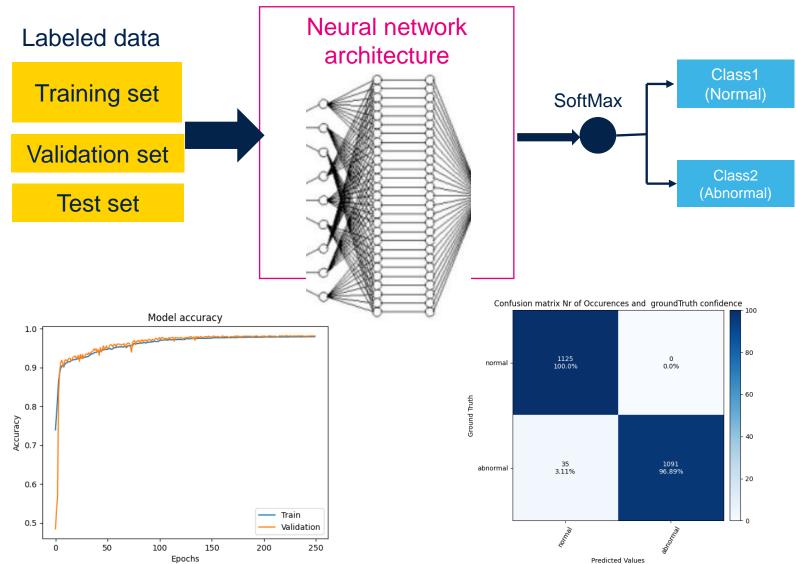




Al model training

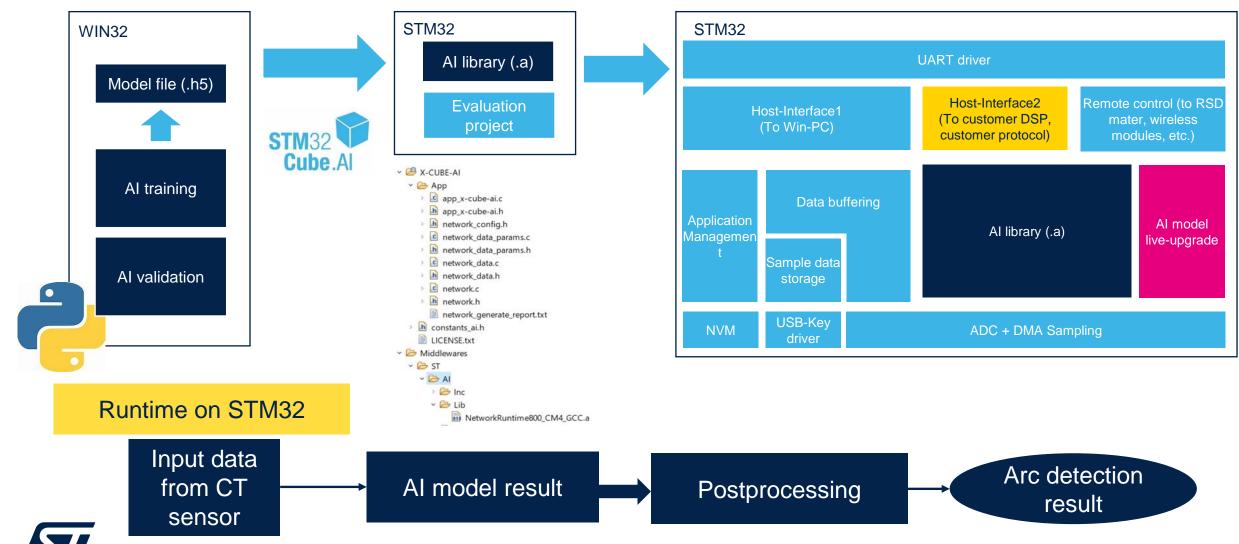
- Collecting dataset by using AFCI GUI with two classes.
 - Normal status
 - Arc status
- Split dataset
 - Training set
 - Validation set
 - Test set







Al model implementation



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Takeaways



Turnkey ref. design to deploy state-of-art AFCI solution efficiently

Deep-learning-based classifier to address high detection accuracy

High performance edge computation with STM32G4 or STM32H7

Flexible and accurate signal processing with TSV7xx amplifiers

Mature support materials and process with experienced team



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